

B<sup>1</sup>

life-time of each said integrated circuit under a testing environment. Moreover, an acceleration factor function also is established under the testing environment. Herein, the acceleration factor function is related to the relationship between a testing time of the testing environment and a real time of the normal operating environment. Moreover, the testing environment is adjusted to let (failure rate)/(unit time) in the testing environment is larger than the (failure rate)/(unit time) in a normal operating environment, and in general it is achieved by increasing working voltage of integrated circuits, increasing temperature, increasing pressure or other ways. Obviously, contents of the acceleration factor function is decided by the difference between the testing environment and the normal operating environment, and the acceleration factor function could be a constant, a linear function or a nonlinear function. Further, as discussed above, the failure rate testing time relation can be divided into three periods in according to value of the testing time, the three periods are a an infant mortality period, a normal life period and a wear out period.

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**Listing of Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

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Claim 1 (currently amended):

B<sup>2</sup>

1.A method for determining failure rate and selecting a best burn-in time, comprising:

providing a plurality of ~~integrate~~ integrated circuits;

performing a life-time testing process, wherein a failure rate testing time relation is established by measuring the life-time of each said integrated circuit under a testing environment, wherein an acceleration factor function also is established under said testing environment, said acceleration factor function being related to the relationship between a